

SCANNING 2007

CALL FOR PAPERS:

Abstract deadline — January 15, 2007

Papers are now being solicited for oral presentation and must be received at SCANNING/FAMS no later than January 15, 2007. Submit online at <http://scanning.msubmit.net> Abstracts will be published in the Proceedings Issue of *SCANNING*[®], *The Journal of Scanning Microscopies*, available at the meeting. In addition, full-length manuscripts may be submitted to *SCANNING* for peer review for publication in another issue. Presentation for contributed papers will be limited to approximately 20 minutes unless an exception is made by the Program Committee. For general meeting information, contact: SCANNING Program Committee, P.O. Box 485, Mahwah, NJ 07430-0485, USA. Phone (201) 818-1010, Fax (201) 818-0086, e-mail: scanning2007@fams.org, Internet: www.scanning.org

All topics in the scanning microscopies are sought, including:

- Advances in confocal and related optical microscopies
- Agricultural applications
- Backscattering electron diffraction
- Biological and biomedical microscopy and microanalysis
- Electron beam specimen interaction workshop
- Focused ion beam (FIB)
- Forensics applications
- Graphic arts aspects of microscopy
- Light microscopy
- Materials microscopy and microanalysis
- Medical applications of scanning microscopy
- Microanalysis in SEM/EPMA/AEM
- Microscopy and microanalysis: theory, instrumentation and techniques
- Microwave technology
- Monte Carlo modeling for microscopy and microanalysis
- Multidimensional microscopy
- Museum applications
- Nanotechnology and nanofabrication
- Scanning cry-HRSEM of chemical systems
- Scanning probe microscopies
- Semiconductor devices, materials, and process characterization
- STEM
- TEM
- X-ray mapping in electron beam instruments

SHORT COURSES

The Short Courses present information on the subject listed, and the instructor will provide a course packet for each registrant. *Special* registration includes your choice of one short course. Be sure to **REGISTER EARLY** as enrollment is limited.

Short Courses will be scheduled on April 10, April 11, April 12. The Short Course curriculum at **SCANNING 2007** includes:

- Introduction to Atomic Force Microscopy (two-day course)
- Quantitative Measurements using AFM (half day course)
- Materials Science Applications of AFM (half day course)
- Advanced Topics in SEM
- Scanning Microscopy in Forensic Science
- Images in Print

PROGRAM COMMITTEE:

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SCANNING 2007

Tuesday, April 10, Wednesday, April 11, and Thursday, April 12

The Portola Plaza

Monterey • California • USA

Instructions for Preparation of Abstracts

Abstracts:

Please provide an abstract of your proposed presentation at **SCANNING 2007**. Include relevant methods, materials, data, conclusions, references, and illustrations (maximum of two single column width, black and white, high-resolution images or glossy prints images). The charge to authors for publishing either halftones or line drawings is \$92 each. A check (in U.S. funds, drawn on a U.S. bank) for the full amount must be included with the abstract submission. The text of your abstract must be no more than 700 words (references are included in the word count). Noninformational language, such as “will be presented” or “will be discussed” will not be accepted. References must be cited in the text and numbered, per *SCANNING* abstract style.

- **Your abstract should be submitted online to <http://scanning.msubmit.net>.** If it must be submitted by mail, the abstract should be provided on a computer disc (please spell check) and on hard copy (e-mail preferred), and must be accompanied by a completed checklist. Your abstract will be typeset for publication. **Please include up to 5 PACS codes (see www.scanning.org for full PACS list).**
- Equations will be typeset, so kindly provide them in type form rather than hand drawing.
- References should be numbered and cited in the text. Do not underline. Please include the names of all authors (*et al.* is not acceptable), complete title, volume, and inclusive page numbers for every reference.
- An unlabeled color image related to your presentation may be submitted for consideration as the cover of the Proceedings Issue and should be supplied as a 5”x5” high-resolution Tiff file. If more than 5mb, supply file on CD.
- **Deadline: January 15, 2007.** The Program Committee will acknowledge receipt of abstracts. Your abstract, if received before the deadline and accepted for presentation at the meeting, will appear in the Proceedings Issue of *SCANNING, The Journal of Scanning Microscopies*. The Proceedings Issue is the March/April 2007 issue of *SCANNING* and will be distributed at **SCANNING 2007**.
- Abstracts received and accepted for presentation after the deadline will appear in the May/June 2007 issue (late abstracts will not be distributed at the meeting).

Abstracts sent by mail should be addressed to Dr. Robert P. Becker, Editor, Proceedings Issue, *SCANNING*, P.O. Box 485, Mahwah, NJ 07430-0485. For express delivery services (not handled by the U.S. Postal Service), address to 545 Island Road, Suite 3D, Ramsey, NJ 07446-2822, USA. Dr. Becker’s phone: (312) 996-7215, fax: (312) 413-0354, e-mail: scanning2007@fams.org